TRANSFER ANDENTREPRENEUR CENTRE

X-ray diffractometer

The Stresstech Xstress G2R enables users to measure residual stresses in the near-surface area.

Training period for independent usage, without pre knowledge: approx. 16 h

Profile

The Stresstech Xstress G2R is an X-Ray diffractometer for the semi-automatic generation of surface residual stress profiles.

MOS dector resolution	0,03° - 0,06°/ pixel 2 -angle
2 -Area	Adjustable between +100° and 165°
X-ray tube	Maximum exit: 30 kV at 10 mA = 300 watt
Collimator	Interchangeable, point siz: 1,2,3,4 und 5 mm
Measuring distance	Between 50, 75 and 100 mm

Software
- based on Windows (already installed at the Computer)
- d-sin² measuring modus
- - Measuring modus
- Material library included
- Various analysis modes included